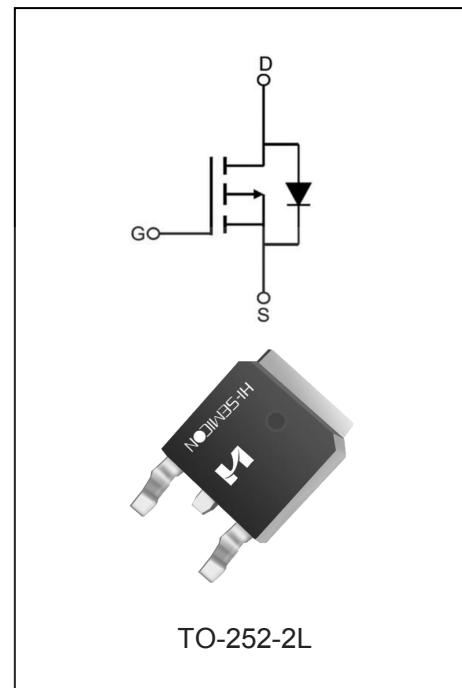


-40A, -40V P-CHANNELMOSFET

GENERAL DESCRIPTION

The SFD4004PT uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. Such as: PWM Applications, Power Management



FEATURES

- ◆ $R_{DS(on)}=11\text{m}\Omega(\text{Typ}) @ V_{GS}=-10\text{V}, I_D=-10\text{A}$
- ◆ $R_{DS(on)}=14\text{m}\Omega(\text{Typ}) @ V_{GS}=-4.5\text{V}, I_D=-10\text{A}$
- ◆ $V_{DS}=-40\text{V}, I_D=-40\text{A}$
- ◆ Advance Trench Technology
- ◆ Fast Switching and High efficiency
- ◆ Lead Free and Green Devices Available: RoHS Compliant

ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SFD4004PT	TO-252-2L	SFD4004PT	Pb Free	Reel

ABSOLUTE MAXIMUM RATINGS ($T_C=25^\circ\text{C}$ unless otherwise noted)

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	-40	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current	I_D	-40	A
$T_C = 100^\circ\text{C}$		-28	
Drain Current Pulsed(Note 1)	I_{DM}	-160	A
Power Dissipation($T_C=25^\circ\text{C}$)	P_D	80	W
Single Pulsed Avalanche Energy (Note 2)	E_{AS}	523	mJ
Operation Junction Temperature Range	T_J	-55~+175	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55~+175	$^\circ\text{C}$

THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	2.6	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	$^\circ\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain -Source Breakdown Voltage	B_{VDSS}	$V_{GS}=0\text{V}, I_D=-250\mu\text{A}$	-40	--	--	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=-40\text{V}, V_{GS}=0\text{V}$	--	--	100	nA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=20\text{V}, V_{DS}=0\text{V}$	--	--	100	nA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=-20\text{V}, V_{DS}=0\text{V}$	--	--	-100	nA
On Characteristics						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=-250\mu\text{A}$	-1.0	-1.5	-2.5	V
Static Drain- Source On State Resistance(Note 3)	$R_{DS(on)}$	$V_{GS}=-10\text{V}, I_D=-10\text{A}$	--	11	13	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-10\text{A}$	--	14	17	
Forward Transconductance	g_{FS}	$V_{GS}=-5.0\text{V}, I_D=-12\text{A}$	--	31	--	S
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{DS}=-20\text{V}$	--	2520	--	pF
Output Capacitance	C_{oss}		--	320	--	
Reverse Transfer Capacitance	C_{rss}		--	305	--	
Total Gate Charge	Q_g	$V_{DS}=-20\text{V} I_D=-12\text{A}$	--	65	--	nC
Gate-Source Charge	Q_{gs}		--	12	--	
Gate-Drain Charge	Q_{gd}		--	13	--	
Switching Characteristics						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=-20\text{V} I_D=-12\text{A}$	--	11	--	ns
Turn-on Rise Time	t_r		--	16	--	
Turn-off Delay Time	$t_{d(off)}$		--	35	--	

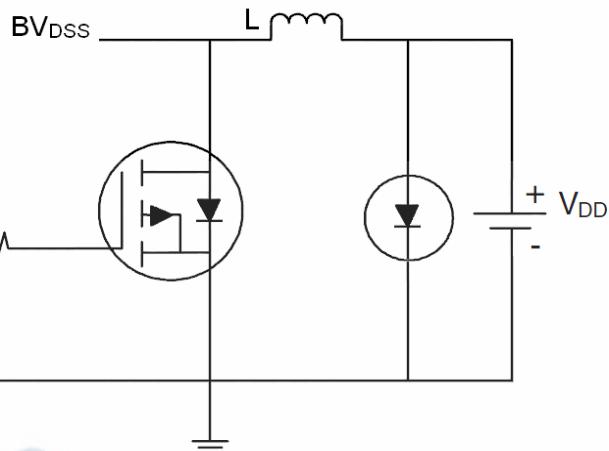
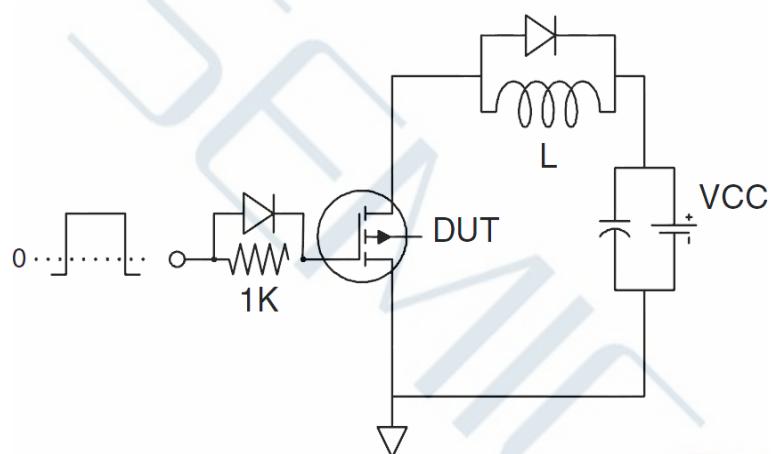
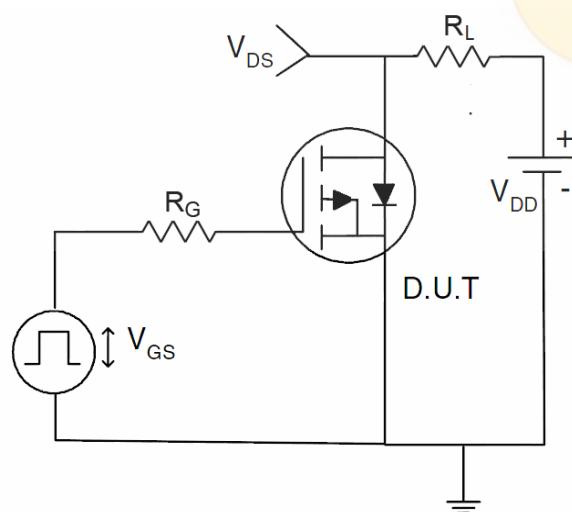
Turn-off Fall Time	t_f	$V_{DD}=-20V$ $I_D=-12A$ $V_{GS}=-12V$ $R_G=2.5\Omega$	--	25	--	ns
--------------------	-------	---	----	----	----	----

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_S	Integral Reverse P-N Junction Diode in the MOSFET	--	--	-40	A
Pulsed Source Current	I_{SM}		--	--	-160	
Diode Forward Voltage	V_{SD}	$I_S=-12A, V_{GS}=0V$	--	--	1.2	V

Notes:

1. Pulse width limited by maximum junction temperature
2. $L=0.5mH, V_{DD}=-20V, V_G=-10V, R_G=25\Omega$, starting $T_J=25^\circ C$
3. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$
4. Essentially independent of operating temperature

TYPICAL TEST CIRCUIT**1) E_{AS} Test Circuit****2) Gate Charge Test Circuit****3) Switch Time Test Circuit**

TYPICAL CHARACTERISTICS

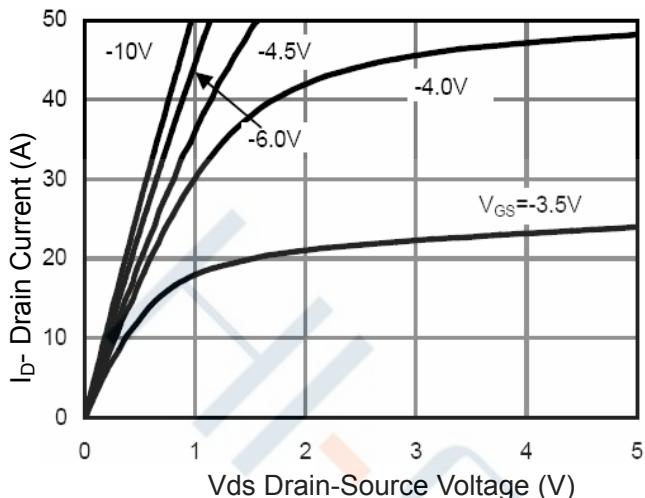


Figure 1 Output Characteristics

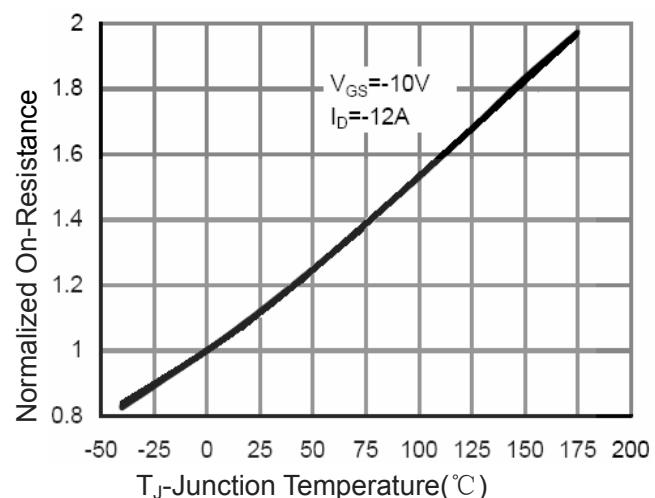


Figure 4 Rdson-Junction Temperature

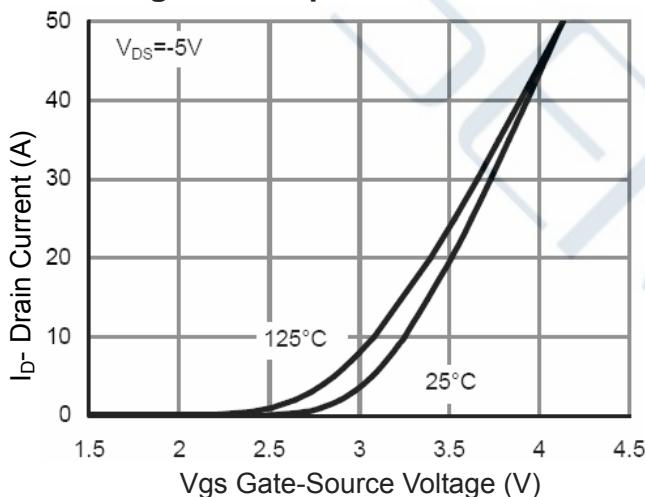


Figure 2 Transfer Characteristics

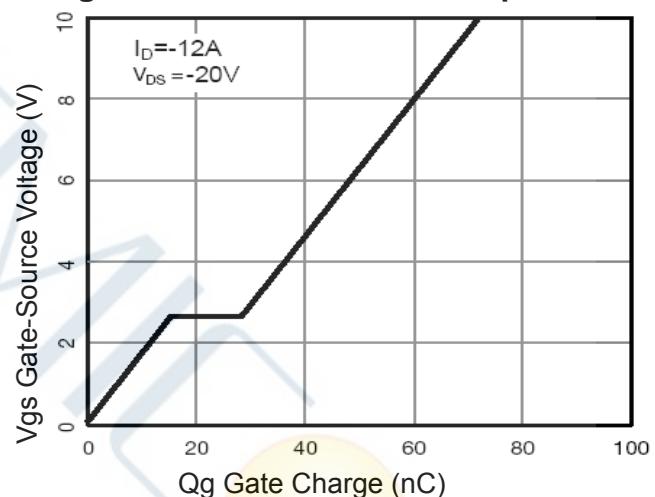


Figure 5 Gate Charge

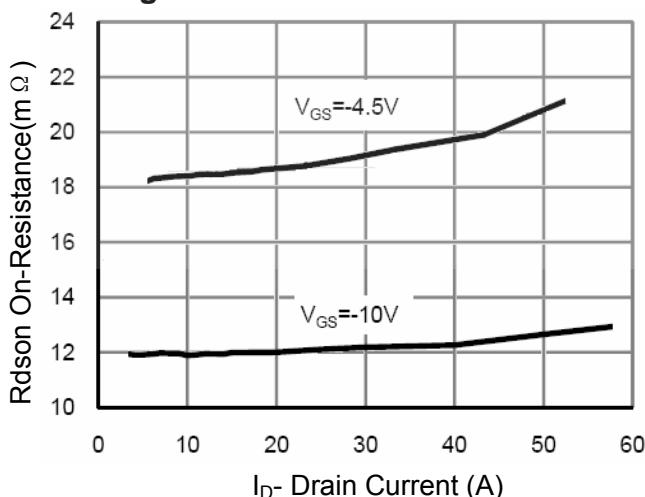


Figure 3 Rdson- Drain Current

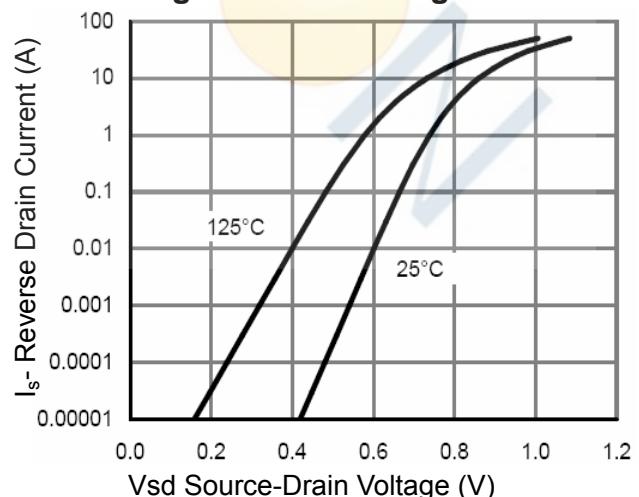


Figure 6 Source- Drain Diode Forward

TYPICAL CHARACTERISTICS

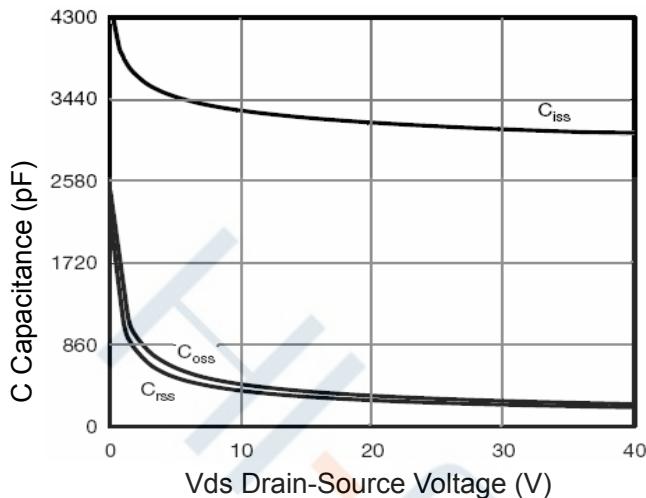


Figure 7 Capacitance vs Vds

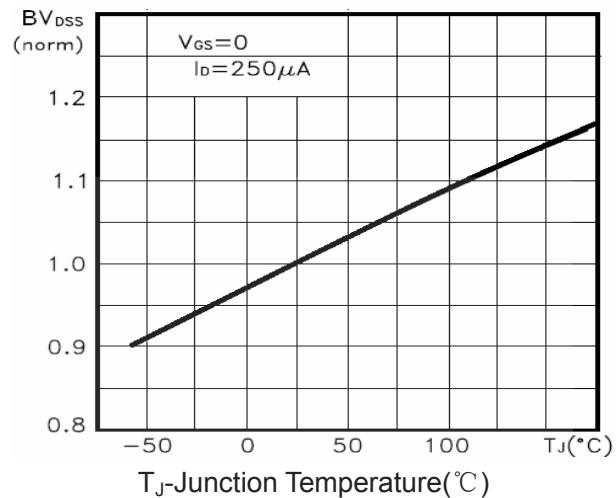
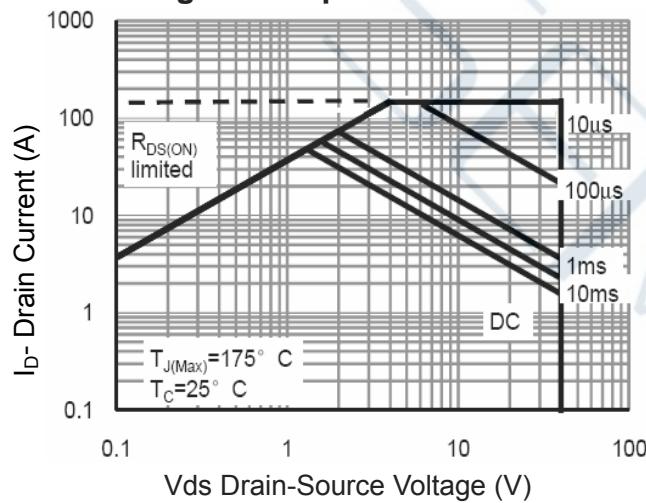
Figure 9 BV_{DSS} vs Junction Temperature

Figure 8 Safe Operation Area

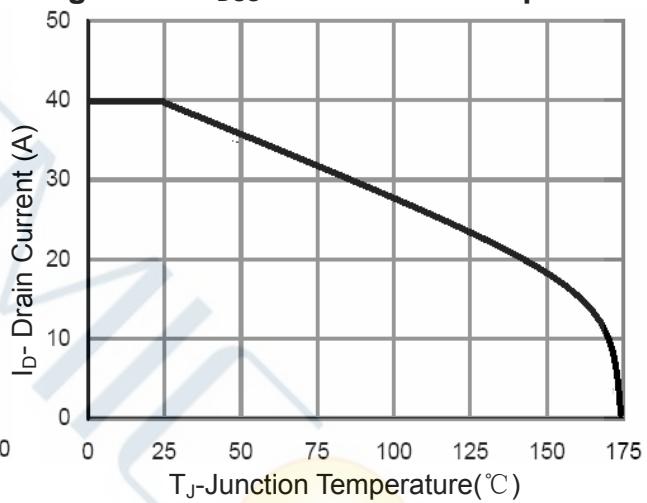
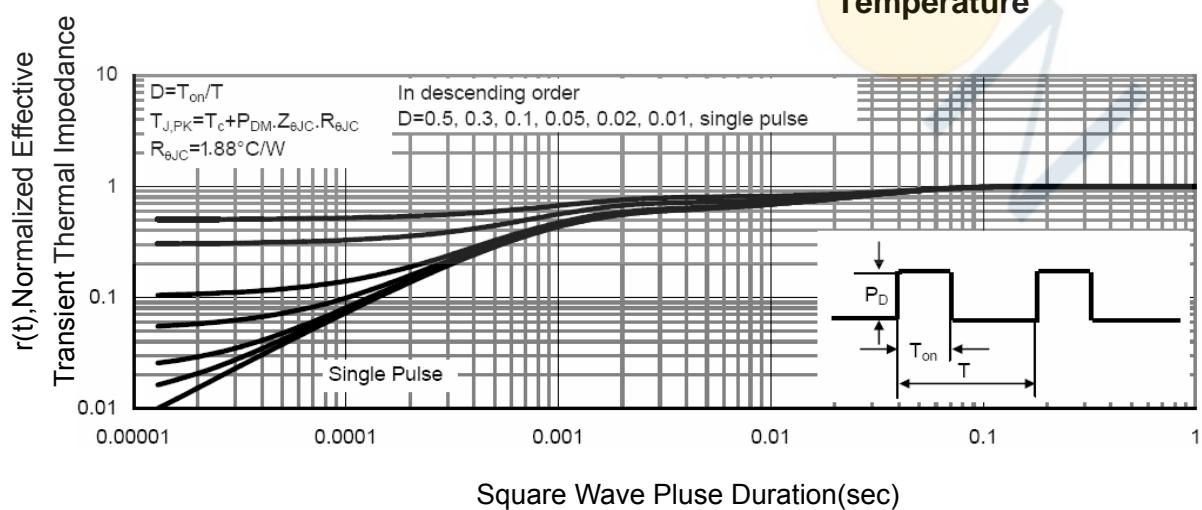
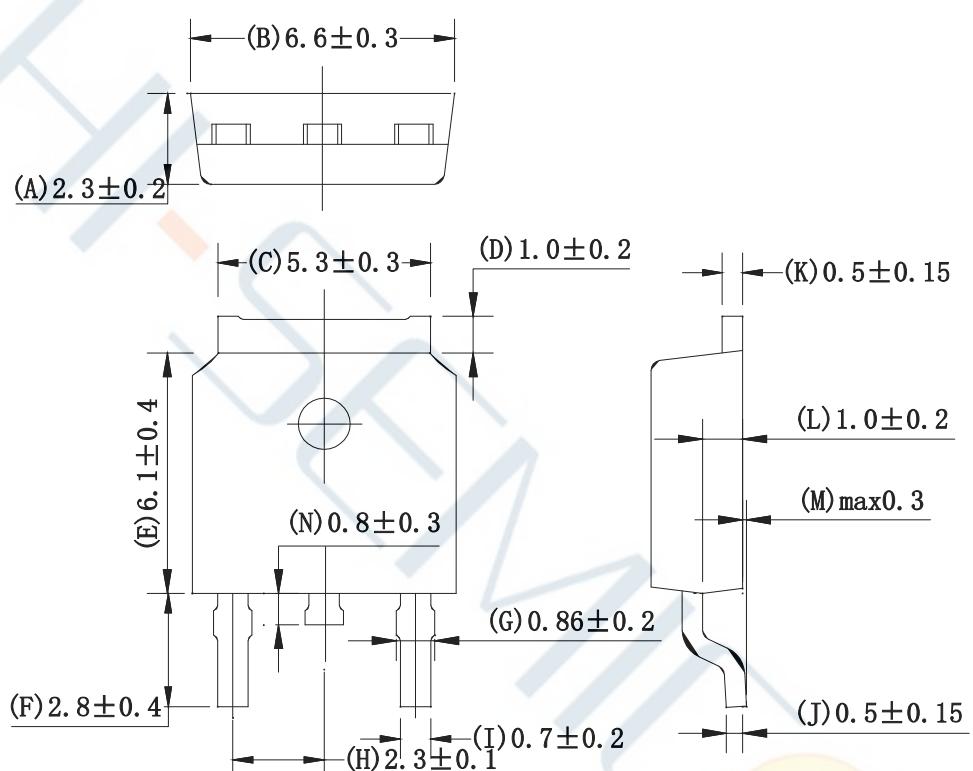
Figure 10 I_D Current Derating vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance

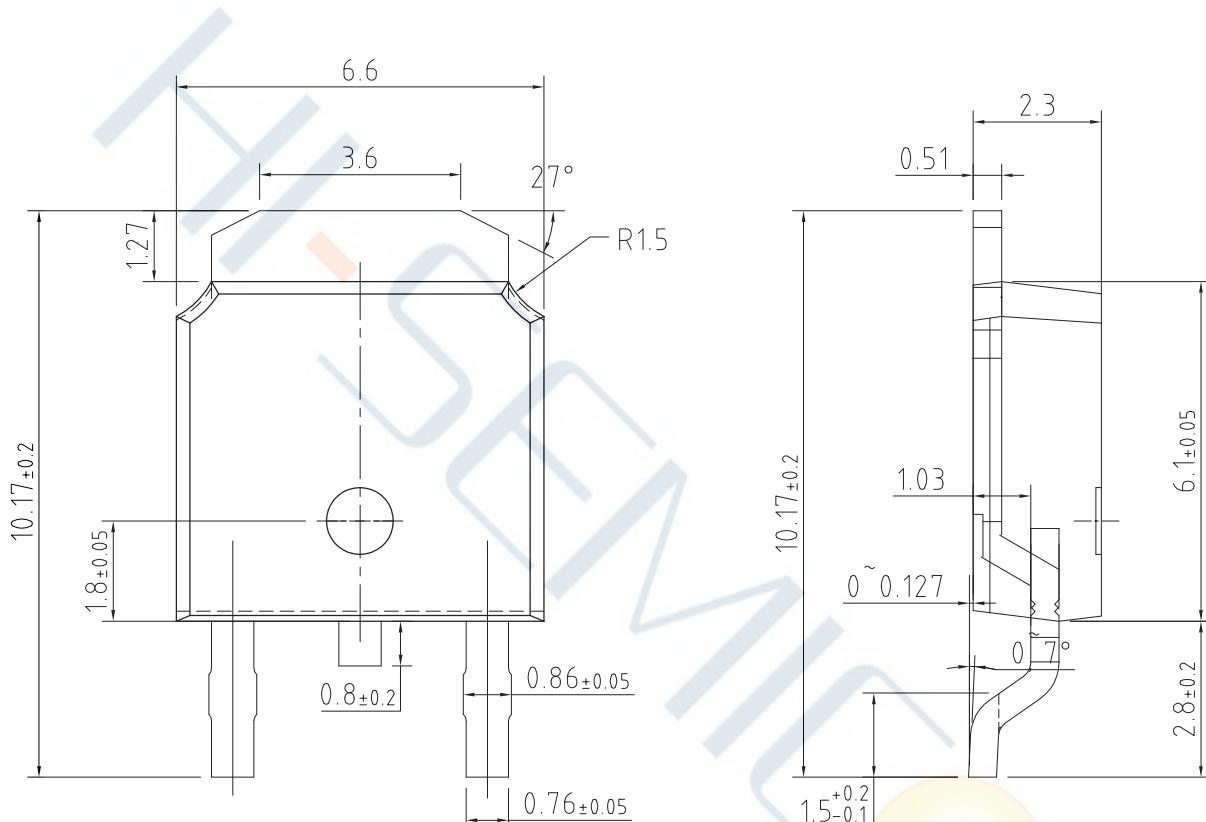
Package Dimensions of TO-252-2L

Unit:mm



Package Dimensions of TO-252-2L

Unit:mm



DISCLAIMER:

- Hi-semicon reserves the right to make changes to the information herein for the improvement of the design and Performance without further notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
- All semiconductor products malfunction or fail with some probability under special conditions. When using Hi-semicon products in system design or complete machine manufacturing, it is the responsibility of the buyer to comply with the safety standards strictly and take essential measures to avoid situations in which a malfunction or failure of such Hi-semicon products could cause loss of body in jury or damage to property.
- Hi-semicon will supply the best possible product for customer!

